

# Contents

**Knowing Your AMS System’s Limits: System Acceptance Region Exploration by Using Automated Model Refinement and Accelerated Simulation** ..... 1  
Georg Gläser, Hyun-Sek Lukas Lee, Markus Olbrich, and Erich Barke

**Designing Reliable Cyber-Physical Systems** ..... 15  
Gadi Aleksandrowicz, Eli Arbel, Roderick Bloem, Timon D. ter Braak, Sergei Devadze, Goerschwin Fey, Maksim Jenihhin, Artur Jutman, Hans G. Kerkhoff, Robert Könighofer, Shlomit Koyfman, Jan Malburg, Shiri Moran, Jaan Raik, Gerard Rauwerda, Heinz Riener, Franz Röck, Konstantin Shibin, Kim Sunesen, Jinbo Wan, and Yong Zhao

**On the Application of Formal Fault Localization to Automated RTL-to-TLM Fault Correspondence Analysis for Fast and Accurate VP-Based Error Effect Simulation: A Case Study** ..... 39  
Vladimir Herdt, Hoang M. Le, Daniel Große, and Rolf Drechsler

**Error-Based Metric for Cross-Layer Cut Determination** ..... 59  
A. Rafiev, F. Xia, A. Iliasov, R. Gensh, A. Aalsaud, A. Romanovsky, and A. Yakovlev

**Feature-Based State Space Coverage Metric for Analog Circuit Verification** ..... 83  
Andreas Fürtig, Sebastian Steinhorst, and Lars Hedrich

**Error-Free Near-Threshold Adiabatic CMOS Logic in the Presence of Process Variation** ..... 103  
Yue Lu and Tom J. Kazmierski

**Index** ..... 115

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